



STN Database Summary Sheet

JAPIO (Japan Patent Information Organization database) is a patent database providing the most comprehensive English-language access to Japanese unexamined patent applications (Kokai Tokkyo Koho) in all technologies, which are provided on PAJ (Patent Abstracts of Japan) CD-ROMS.

The file is enhanced with bibliographic data from INPADOC records from April 1973 to end of 1997.

Records contain assignee data, publication information, International Patent Classification codes, as well as title and abstract in English. Abstracts are available for all applications originating in Japan and for many foreign applications. Images of front page drawings, when available for a given patent, are included. Any program that handles TIFF and JPEG images compressed in Group 4 fax format, e.g., STN Express, may be used to capture graphic images from DISPLAY or they may be viewed directly on the screen during an STN on the Web session.

Subject Coverage

- All areas of science and technology, i.e., all classes of the International Patent Classification

Sources

- Patent Abstracts of Japan (CD-ROM), Unexamined Applications
- INPADOC database

File Data

- October 1976 to the present for PAJ data
- April 1973 to 1977 for INPADOC data
- More than 7.7 million records (10/02)
including 1.6 million INPADOC records
- More than 5.1 million images (10/02)
- Updated monthly with about 25,000 records
- Automatic current-awareness searches (SDIs) are run monthly

User Aids

- Online Helps (HELP DIRECTORY lists all help messages available)
- STNGUIDE

Database Producer

Japanese Patent Office
3-4-3, Kasumigaseki
Chiyoda-ku, Tokyo 100-8915
Japan
Phone: (+81) 3/3581-0762
Copyright Holder

Database Supplier

FIZ Karlsruhe
P.O. Box 2465
D-76012 Karlsruhe
Germany
Phone: (+49) 7247/808-555
Fax: (+49) 7247/808-259
E-mail: helpdesk@fiz-karlsruhe.de

In Europe

STN International
c/o FIZ Karlsruhe
Postfach 2465
76012 Karlsruhe
Germany
Phone: (+49) 7247/808-555
Telex: 17724710+
Telefax: (+49) 7247/808-131
STNmail: HLPDESKK

In Japan

STN International
c/o Japan Science and Technology
Corporation (JST)
5-3 Yonbancho, Chiyoda-ku
Tokyo 102-8666, Japan
Phone: (+81) 3-5214-8414
Telefax: (+81) 3-5214-8410
STNmail: HLPDESKT

In North America

STN International
c/o CAS
P.O. Box 3012
Columbus, Ohio 43210 U.S.A.
Phone: (614) 447-3731
Telefax: (614) 447-3751
STNmail: HLPDESKC

Search and Display Field Codes

The field that allows left truncation (/BI) is marked with an asterisk (*).

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index * (contains single words from title (TI) and abstract (AB) fields) (1)	None (or /BI)	S ELECTRONIC PUBLISHING S VIDEO(1W)RECORDER (L) ELECTRONICS S L1 AND ?SYSTEM?	AB, TI
Accession Number	/AN	S 2002-064999/AN	AN
Application Country (code and text)	/AC	S JP/AC AND L7	AI
Application Date (2)	/AD	S 2 OCT 1998/AD	AI
Application Number (3)	/AP	S 1991JP-0052634/AP S JP1991-52634/AP	AI
Application Year (2)	/AY	S 1998/AY	AI
Document Type (code and text)	/DT	S L7 AND P/DT	DT
Entry Date	/ED	S L1 AND ED>=20020600	ED
Field Availability	/FA	S L1 AND GI/FA S L1 NOT NOAB/FA	FA
Graphical Image Size (2)	/GIS	S GIS > 32000	GIS
Graphical Image Type	/GIT	S TIF/GIT	GIT
International Patent Classification (contains ICM and ICS)	/IC	S G06F/IC S G06F015/IC S G06F015-40/IC	IC, ICM, ICS
IPC, Additional (Supplementary)	/ICA	S G01B003/ICA	ICA
IPC, Index (Complementary)	/ICI	S B08B101:08/ICI	ICI
IPC, Main	/ICM	S H02M/ICM S H02M003/ICM S H02M003-155/ICM	IC, ICM
IPC, Secondary	/ICS	S G11B027-00/ICS	IC, ICS
IPC Main Group, Range Searchable (2)	/MGR	S C09K/ICM(S)18-20/MGR	IC, ICM, ICS
IPC Sub Group, Range Searchable (2)	/SGR	S C09K011/ICM(S)8000-20000/SGR	IC, ICM, ICS
Inventor	/IN (OR /AU)	S HONMA HIDEO/IN	IN
Language (code and text)	/LA	S JP/LA AND L10	LA
Patent Assignee (4)	/PA (or /CS)	S DAINIPPON PRINT?/PA	PA
Patent Country (code and text)	/PC	S L7 AND JP/PC	PI
Patent Kind Code	/PK	S ENERGY EXCHANG? AND JPA/PK	PI
Patent Number (3)	/PN (or /PATS)	S JP06096131/PN	PI
Priority Country (code and text)	/PRC	S AU/PRC	PRAI
Priority Date (2)	/PRD	S AUSTRALIA/PRC S 29 MAY 1992/PRD	PRAI
Priority Date, First (2)	/PRDF	S 29 MAY 1992/PRDF	PRAI
Priority Number (3)	/PRN	S FR1992-13039/PRN S 1992FR-0013039/PRN	PRAI
Priority Year (2)	/PRY	S 1989/PRY	PRAI
Priority Year, First (2)	/PRYF	S 1989/PRYF	PRAI
Publication Date (2)	/PD	S 19990629/PD	PI
Publication Year (2)	/PY	S 1992/PY	PI
Source (contains volume number) (5)	/SO	S VOL 2001/SO	SO
Title	/TI	S DC-DC CONVERTER##/TI	TI
Update Date (2)	/UP	S L1 AND UP>=20020600	UP

(1) In addition to right truncation, left, and simultaneous left and right truncation are available in the Basic Index. At least 4 characters need to be used for the length of the stem.

(2) Numeric search field that may be searched using numeric operators or ranges.

(3) Either STN format or Derwent format may be used.

(4) Search with implied (S) proximity is available in this field.

(5) The source is PATENT ABSTRACTS OF JAPAN (CD-ROM), Unexamined Applications.

Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group (1) IPC	/APPS /IPC	/AP, /PRN /IC, /ICA, /ICI	S 1991JP-0052634/APPS S JP1991-52634/APPS S G11B027/IPC	AI, PRAI IC, ICA, ICI, ICM, ICS

(1) Either STN format or Derwent format may be used.

DISPLAY and PRINT Formats

Any combination of display fields and formats may be used to display or print answers. Multiple codes must be separated by commas or spaces, e.g., D L1 1-5 TI PA. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for all searchable fields except DT, FA, GI, LA, and SO. Highlighting must be ON during SEARCH in order to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB AI (AP) (1) AN DT (TC) (2,3) ED (2,3) FA (2) GI (4) GIS (2,3) GIT (2,3) ICA (2) ICI (2) ICM (2) ICS (2) IN (AU) LA (2,3) PA (CS) PI (PATS, PN) (1) PRAI (PRN) (1) SO TI (2) UP (2,3)	Abstract Application Information Accession Number Document Type Entry Date Field Availability Graphic Image Graphic Image Size Graphic Image Type IPC, Additional (Supplementary) IPC, Index (Complementary) IPC, Main IPC, Secondary Inventor Language Patent Assignee Patent Information Priority Information Source Title Update Date	D TI PA AB 5,7 D AI PI D AN D DT D ED D FA D GI D GIS D GIT D ICA D ICI D ICM D ICS D IN PA TI D PA D IN PA PI D PI D PI PRAI 1-5 D SO D TI D UP
ABS ALL (1) ALLG (1,4) APPS (1) BIB (1) BIBG (1,4) DALL (1) IALL (1) IALLG (1,4) IBIB (1) IC (2) IND (2) IPC (2) ISTD (1)	AN, AB AN, TI, IN, PA, PI, AI, PRAI, SO, IC (ICM, ICS), ICA, ICI, AB ALL plus GI AI, PRAI AN, TI, IN, PA, PI, AI, PRAI, SO BIB plus GI ALL, delimited for post-processing ALL, indented with text labels IALL plus Graphic Image BIB, indented with text labels ICM, ICS IC (ICM, ICS), ICA, ICI IC (ICM, ICS), ICA, ICI STD, indented with text labels	D TI PA ABS D ALL D ALLG D APPS D BIB D BIBG D DALL D IALL 1-3 D IALLG D IBIB D TI PA IC 10- D TI PA IND D IPC D ISTD

JAPIO**DISPLAY and PRINT Formats (cont'd)**

Format	Content	Examples
SCAN (2,5) STD (1)	TI AN, TI, IN, PA, PI, AI, PRAI, SO, IC (ICM, ICS), ICA, ICI (STD is the default)	D SCAN D STD L2 7
STDG (1,4) TRIAL (TRI, SAMPLE, SAM) (2)	STD plus GI TI, IC (ICM, ICS), ICA, ICI, FA	D STDG D TRI TOTAL
HIT KWIC OCC (2)	Fields containing hit terms Hit terms with 20 words on either side (KeyWord-In-Context) Number of occurrences of hit terms and fields in which they occur	D HIT D KWIC NOH D OCC

- (1) By default, patent numbers, application and priority numbers are displayed in STN format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN format, enter SET PATENT STN.
- (2) No online display fee for this format.
- (3) Custom display only.
- (4) Any program that handles TIFF and JPEG images compressed in Group 4 fax format, e.g., STN Express, may be used to capture graphic images from DISPLAY or they may be viewed directly on the screen during an STN on the Web session.
- (5) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

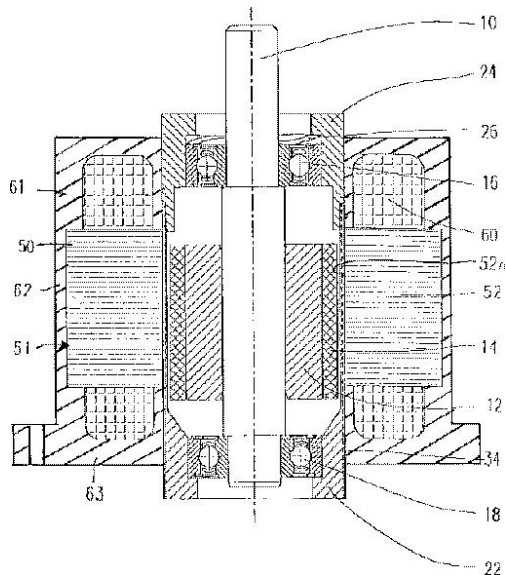
The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y (2)	N
Accession Number	AN	Y	N
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Information	AI	Y (3)	Y
Application Number	AP	Y	Y
Application Number Group	APPS	Y (4)	N
Author (Inventor)	AU	Y (5)	Y
Corporate Source (Patent Assignee)	CS	Y (6)	Y
Document Type	DT	Y (7)	N
Entry Date	ED	Y	Y
Field Availability	FA	Y (7)	N
Graphic Image Size	GIS	Y	Y
Graphic Image Type	GIT	Y	Y
International Patent Classification (IPC)	IPC	Y (8)	N
Inventor	IN	Y	Y
IPC, Additional (Supplementary)	ICA	Y	Y
IPC, Index (Complementary)	ICI	Y	Y
IPC, Main	ICM	Y	Y
IPC, Main and Secondary	IC	Y	Y
IPC, Secondary	ICS	Y	Y
Language	LA	Y (7)	N
Occurrence Count of Hit Terms	OCC	N	Y
Patent Assignee	PA	Y	Y
Patent Country	PC	Y	Y
Patent Information	PI	Y (9)	Y
Patent Kind Code	PK	Y	Y

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Patent Number	PN	Y	Y
Patent Number Group	PATS	Y (10)	N
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y
Priority Date, First	PRDF	Y	Y
Priority Information	PRAI	Y (11)	Y
Priority Number	PRN	Y	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Source	SO	Y (7)	N
Subclass	SCL	Y (12)	N
Subclass Additional	SCLA	Y (13)	N
Subclass Group	SCG	Y (12)	N
Subclass Group Additional	SCGA	Y (13)	N
Subclass Group Main	SCGM	Y (12)	N
Subclass Group Secondary	SCGS	Y (14)	N
Subclass Main	SCLM	Y (12)	N
Subclass Secondary	SCLS	Y (14)	N
Title	TI	Y (default)	Y
Treatment Code	TC	Y (7,15)	N
Update Date	UP	Y	

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
(2) Appends /BI to the terms created by SELECT.
(3) Selects or analyzes the Application Number and appends /AP to the terms created by SELECT.
(4) Selects or analyzes the Application and Priority Numbers and appends /APPS to the terms created by SELECT.
(5) Appends /IN to the terms created by SELECT.
(6) Appends /PA to the terms created by SELECT.
(7) SELECT HIT and ANALYZE HIT are not valid with this field.
(8) Selects or analyzes the ICM, ICS, ICA, and ICI and appends /IPC to the terms created by SELECT.
(9) Selects or analyzes the Patent Number and appends /PN to the terms created by SELECT.
(10) Selects or analyzes the Patent Number and appends /PATS to the terms created by SELECT.
(11) Selects or analyzes the Priority Numbers and appends /PRN to the terms created by SELECT.
(12) Appends /ICM to the terms created by SELECT.
(13) Appends /ICA to the terms created by SELECT.
(14) Appends /ICS to the terms created by SELECT.
(15) Appends /DT to the terms created by SELECT.

JAPIO**Sample Records****DISPLAY IALLG**

ACCESSION NUMBER: 2002-064965 JAPIO
 TITLE: INNER-ROTOR MOTOR ROTOR ASSEMBLY, INNER-ROTOR MOTOR
 AND MANUFACTURING METHOD OF INNER-ROTOR MOTOR
 INVENTOR: RAPP HARALD
 PATENT ASSIGNEE(S): MINEBEA CO LTD
 PATENT INFORMATION:

PATENT NO	KIND	DATE	ERA	MAIN IPC
JP 2002064965	A	20020228	Heisei	H02K021-14

APPLICATION INFORMATION

STN FORMAT: JP 2001-206547 20010706
 ORIGINAL: JP2001206547 Heisei
 PRIORITY APPLN. INFO.: DE 2000-10034302 20000714
 SOURCE: PATENT ABSTRACTS OF JAPAN (CD-ROM), Unexamined
 Applications, Vol. 2002

INT. PATENT CLASSIF.:

MAIN: H02K021-14
 SECONDARY: H02K015-02
 ADDITIONAL: H02K015-03

ABSTRACT:

PROBLEM TO BE SOLVED: To provide a rotor assembly and an inner-rotor motor which can be assembled accurately, easily and at a low cost, can prevent ferromagnetic particles produced from a permanent magnet and external contaminants from penetrating into air gaps in an assembly work and in an operation and can achieve the high rotation precision and the dimensional reduction.

SOLUTION: A rotor 2 comprising a rotor shaft 10 supported by bearings 16 and 18 and rotating a rotary medium mechanically and a permanent magnet 14 formed coaxially on the rotor shaft 10 is provided in a protective cylinder unit 20 comprising receptacles 32 and 42 receiving the bearings 16 and 18 airtightly and a sleeve 30 formed between the receptacles 32 and 42 to form a rotor assembly 1. The rotor assembly 1 is inserted into the center hole of a laminated core 52 of a stator 51 without a circumferential play and fixed to construct an inner-rotor motor.

COPYRIGHT: (C)2002,JPO